

RF Interference Potential Test Report

Measurement performed on February 09, 2025

Device Under Test

Manufacturer	Model
Samsung Electronics	SM-S937U

Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

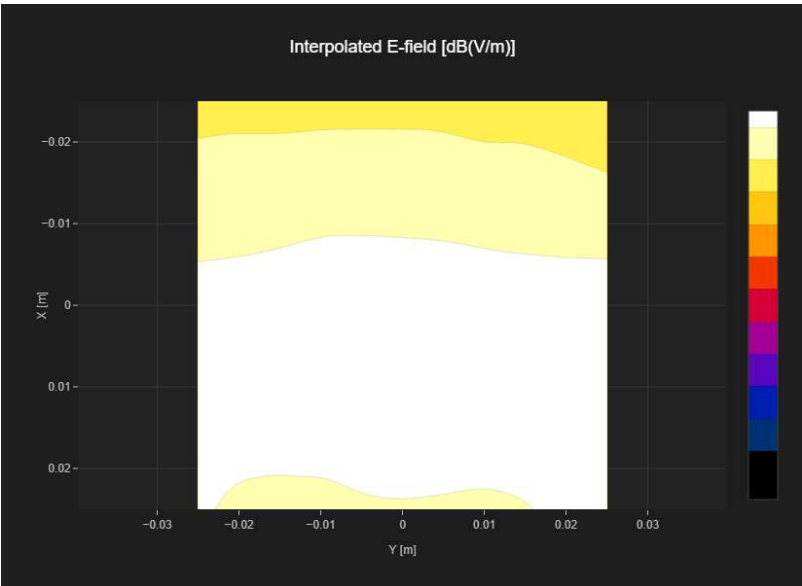
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	128	824.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
19.09	18.26	3.63	21.89



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

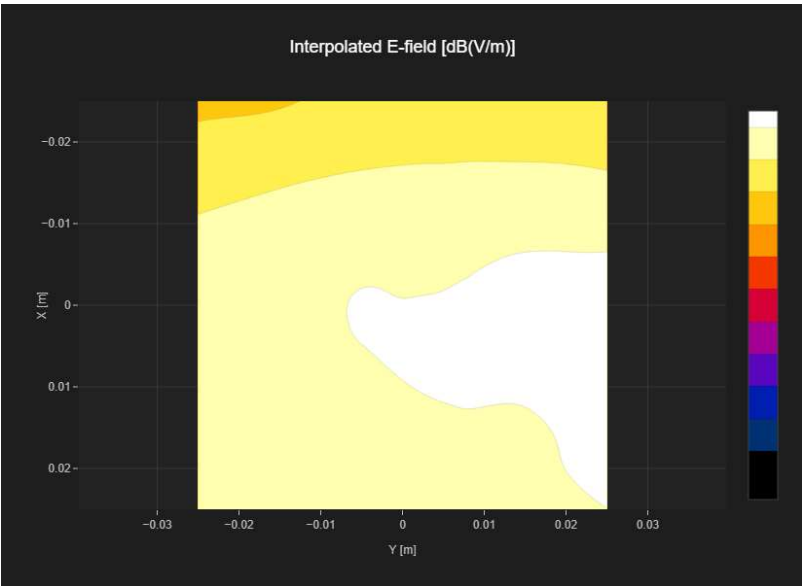
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	190	836.6

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
19.36	18.63	3.63	22.26



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

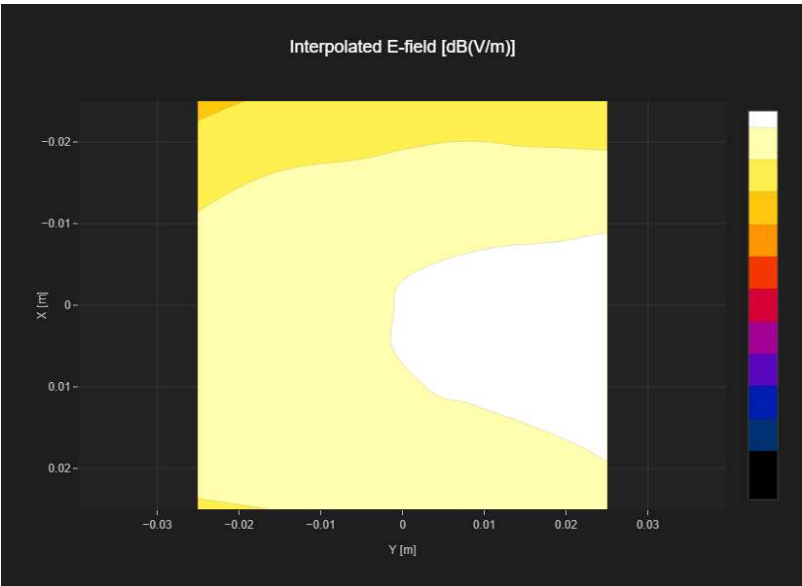
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	251	848.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
20.43	19.27	3.63	22.9



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Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

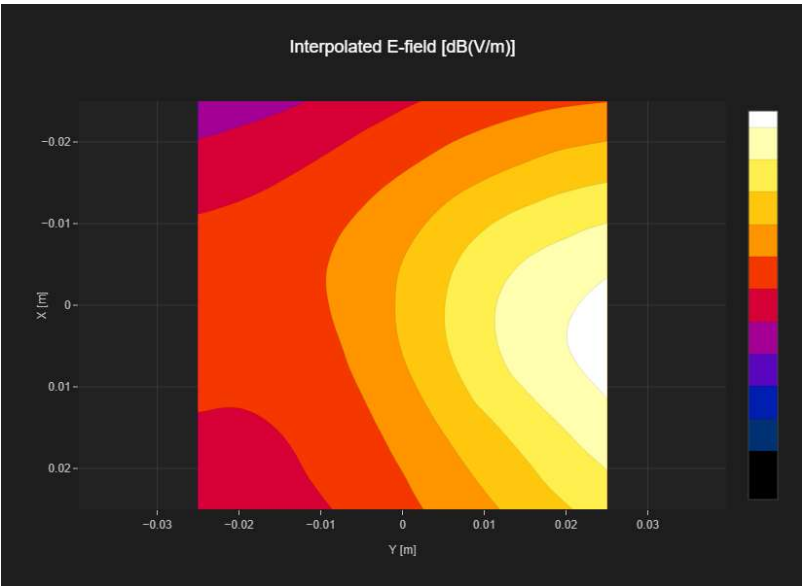
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	128	824.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
39.16	33.08	3.63	36.71



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

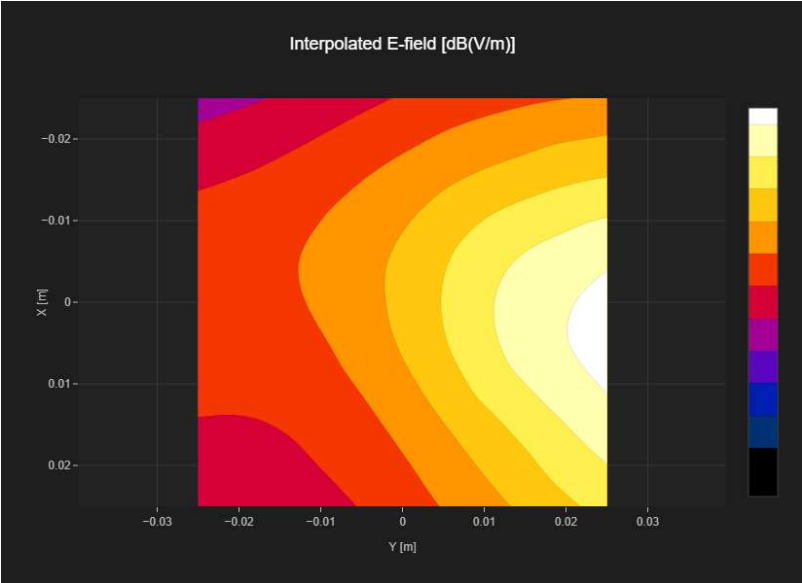
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	190	836.6

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
39.25	33.29	3.63	36.92



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

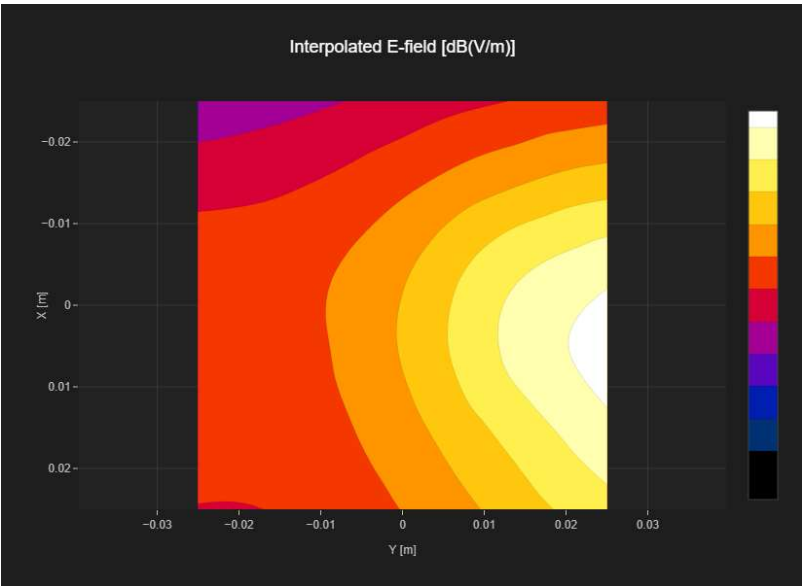
Band Name	Communication Systems Name	Channel	Frequency [MHz]
GSM 850	GSM-FDD (TDMA, GMSK)	251	848.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
38.42	32.28	3.63	35.91



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

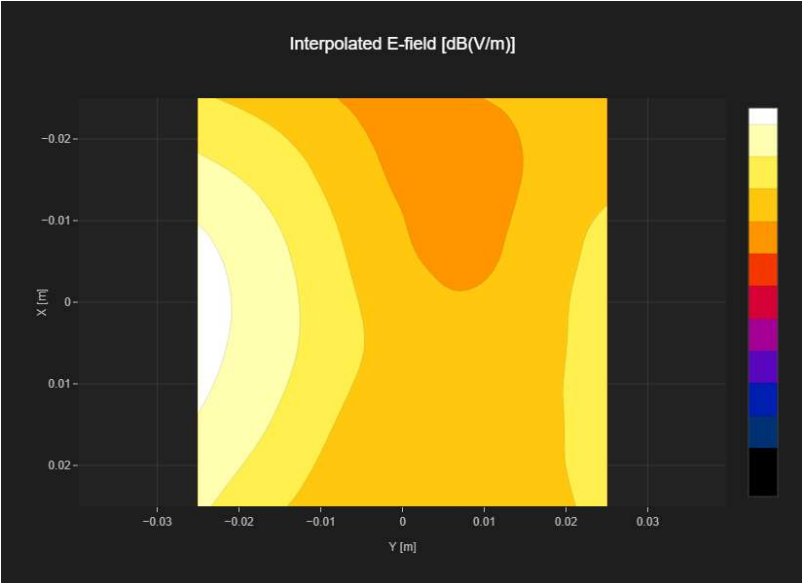
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	512	1850.2

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
22.31	18.13	3.63	21.76



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Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

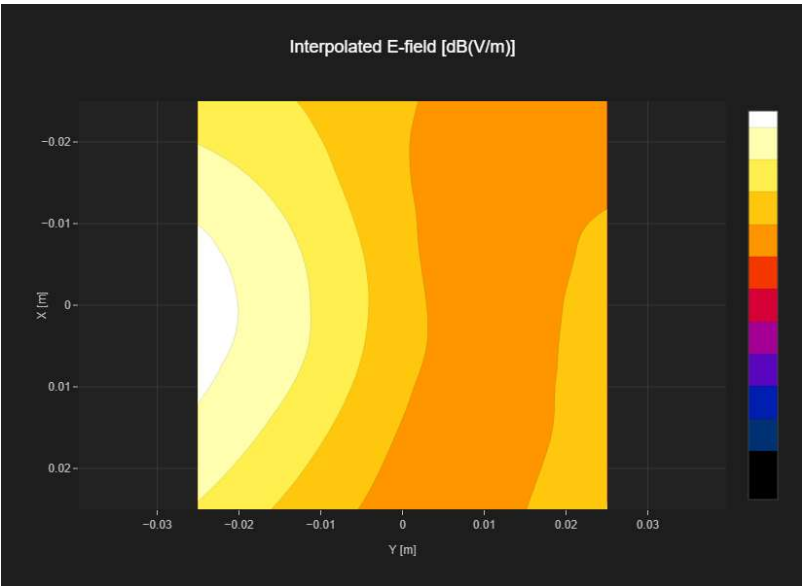
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	661	1880.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.49	18.94	3.63	22.57



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Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

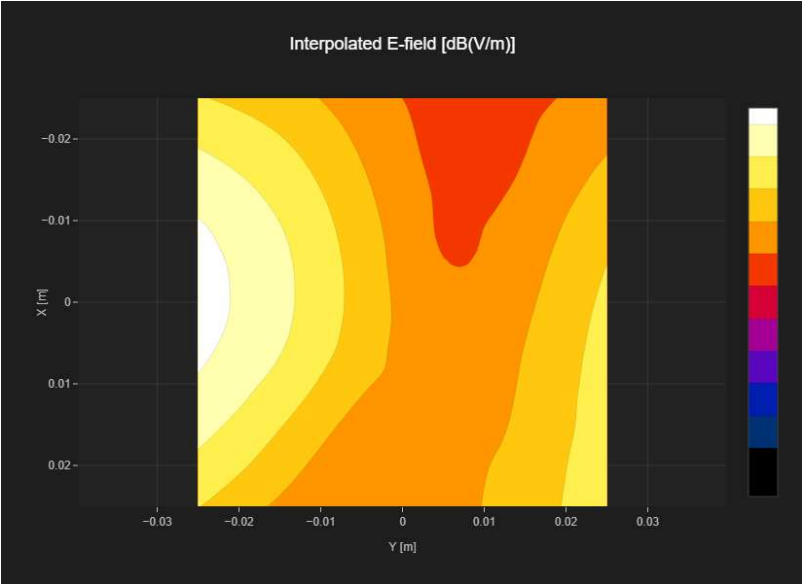
Band Name	Communication Systems Name	Channel	Frequency [MHz]
PCS 1900	GSM-FDD (TDMA, GMSK)	810	1909.8

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
23.85	18.85	3.63	22.48



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

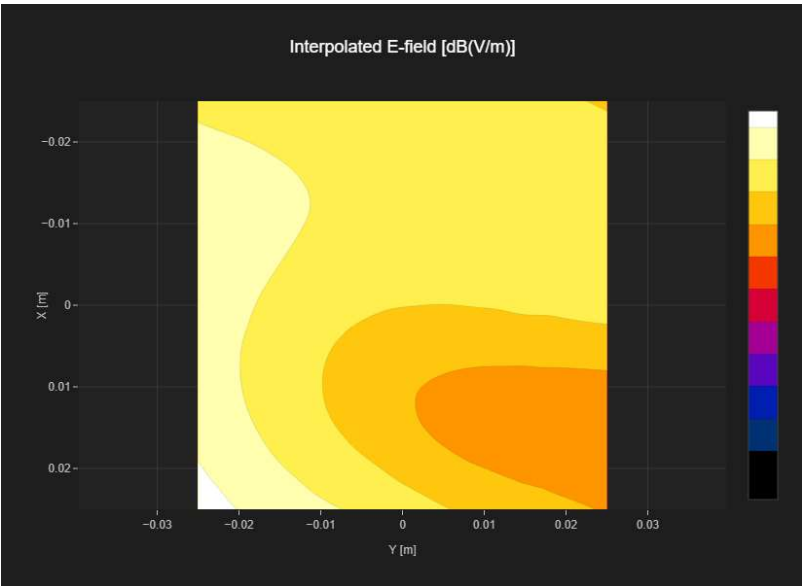
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	39750	2506.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
25.48	21.93	-1.44	20.31



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

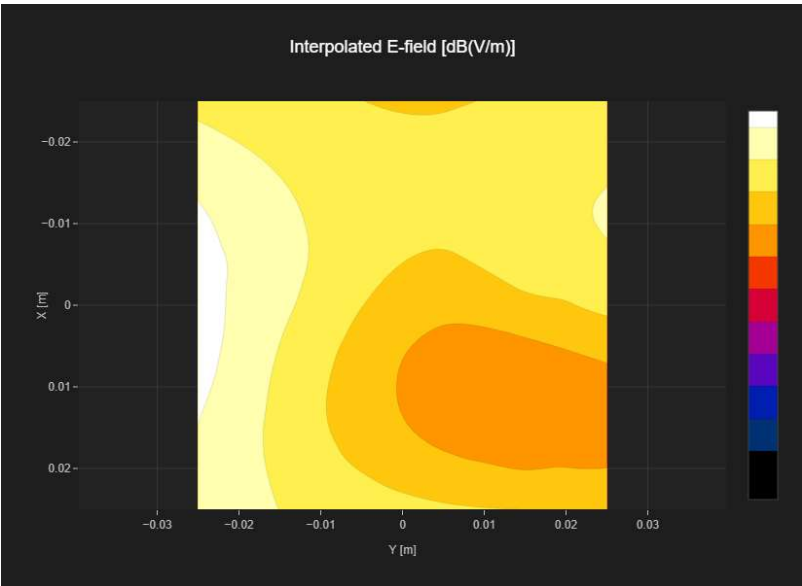
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	40620	2593.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
25.02	21.33	-1.44	19.89



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

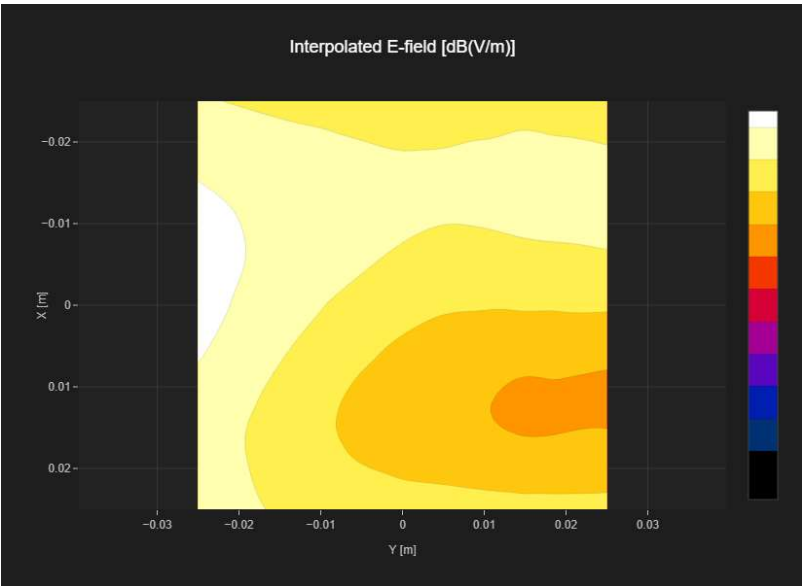
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	41490	2680.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
24.67	21.67	-1.44	20.05



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Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

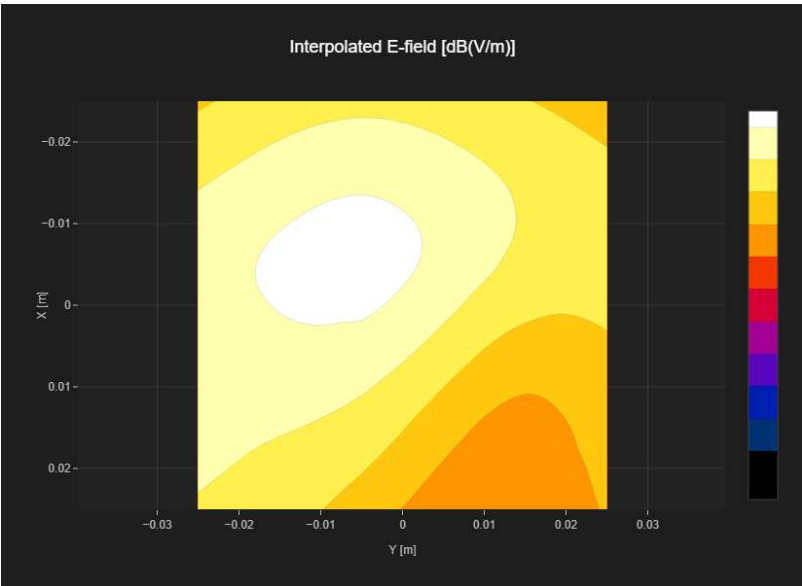
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	39750	2506.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
33.66	30.94	-1.44	29.32



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

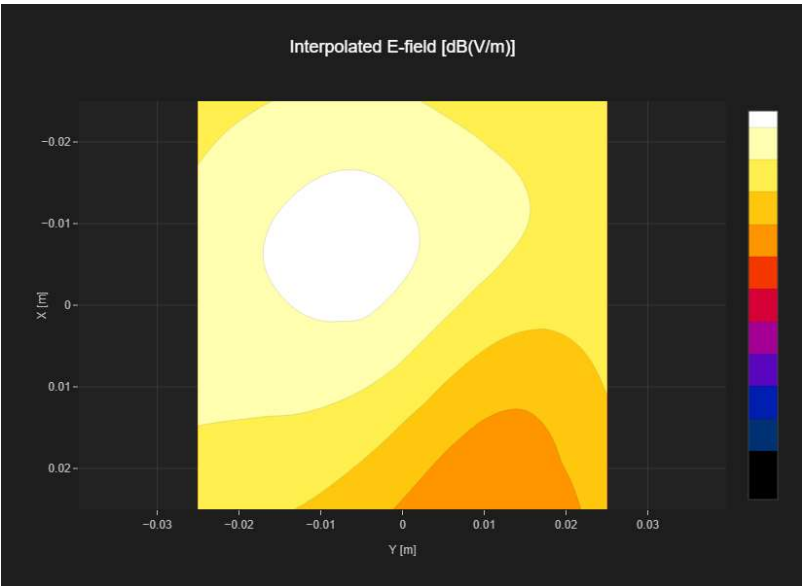
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	40620	2593.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
33.95	31.33	-1.44	29.71



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

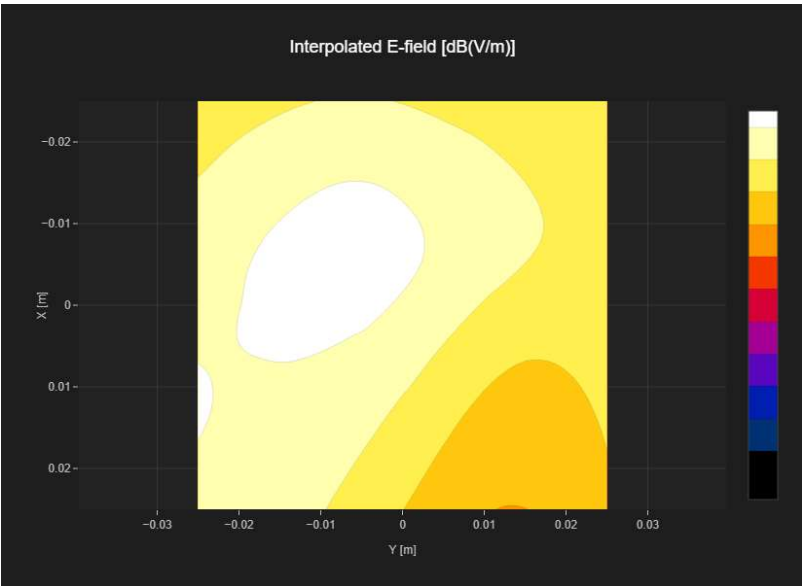
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band 41	LTE-TDD (SC-FDMA, 1 RB, 20 MHz, 16-QAM)	41490	2680.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
33.1	30.98	-1.44	29.36



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

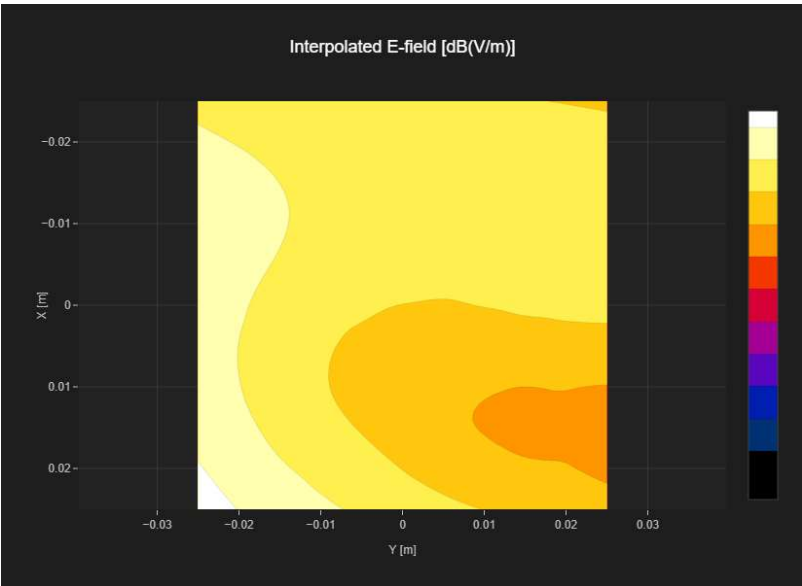
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	509202	2546.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
24.17	20.64	-1.64	19.0



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

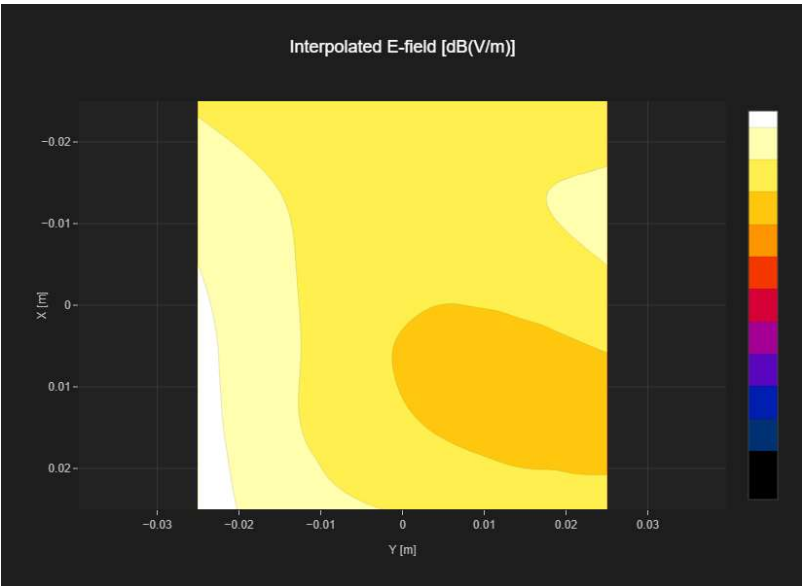
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	518598	2592.99

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
22.84	19.83	-1.64	18.19



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

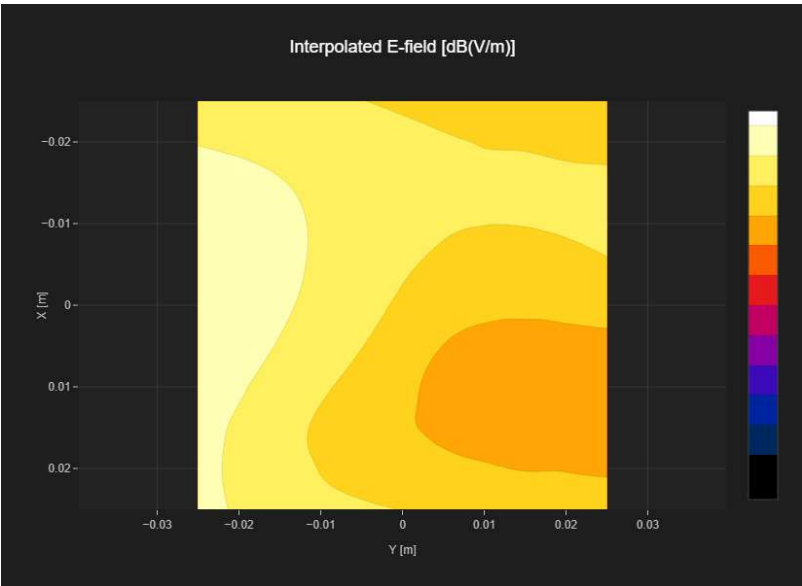
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	528000	2640.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
24.0	20.85	-1.64	19.21



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

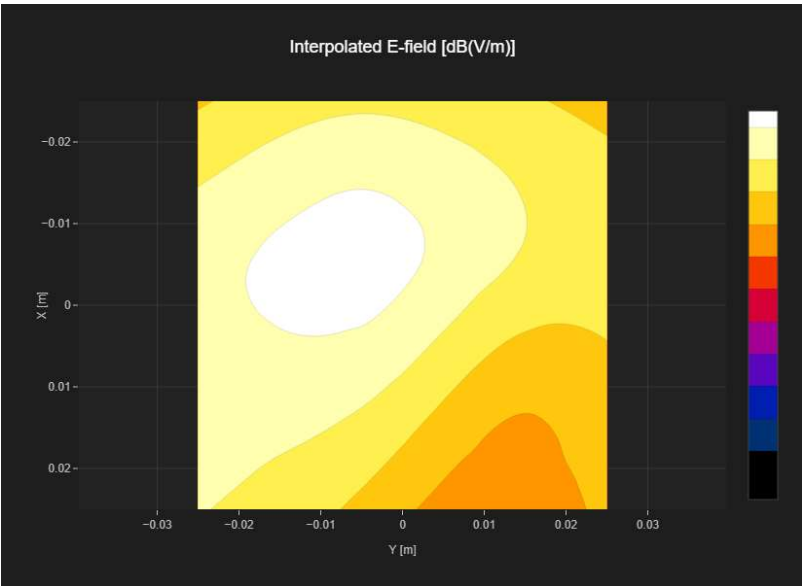
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	509202	2546.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

E _{max} [dB(V/m)]	E _{avg50x50 max} [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
31.56	29.02	-1.64	27.38



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

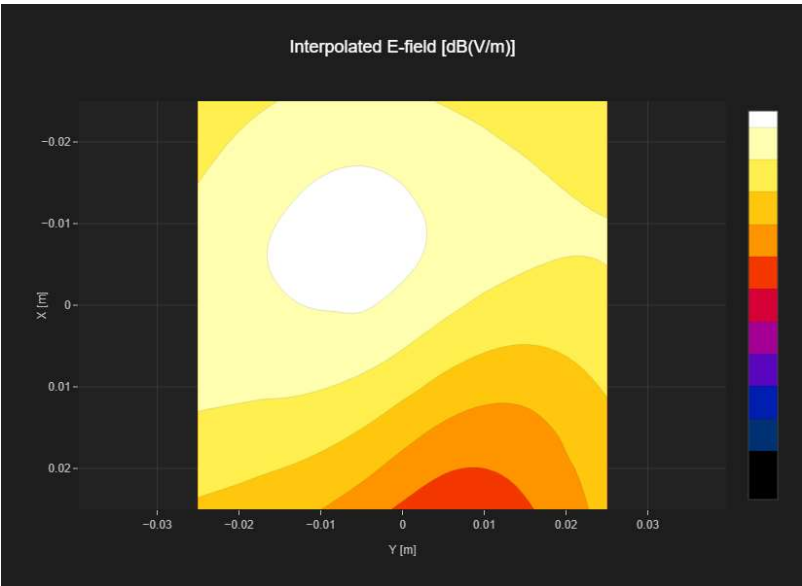
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	518598	2592.99

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
32.02	29.31	-1.64	27.67



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Communication Systems

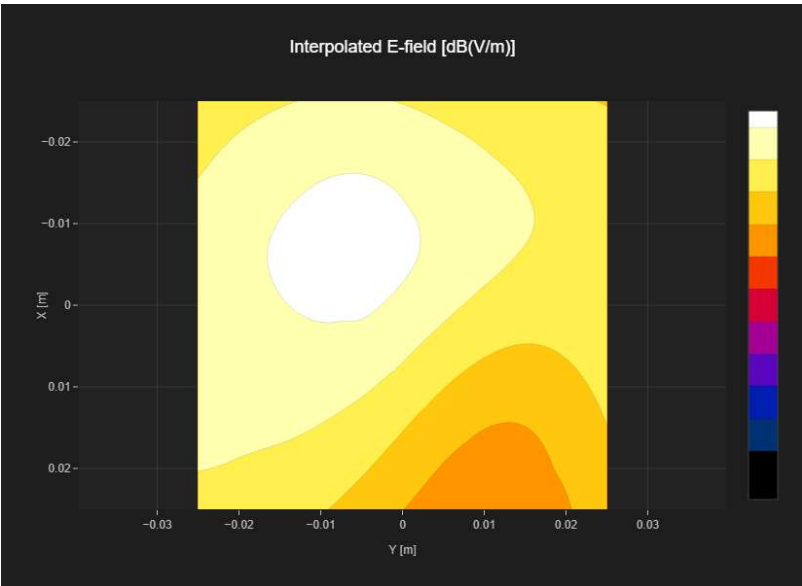
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n41	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	528000	2640.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
31.92	29.39	-1.64	27.75



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

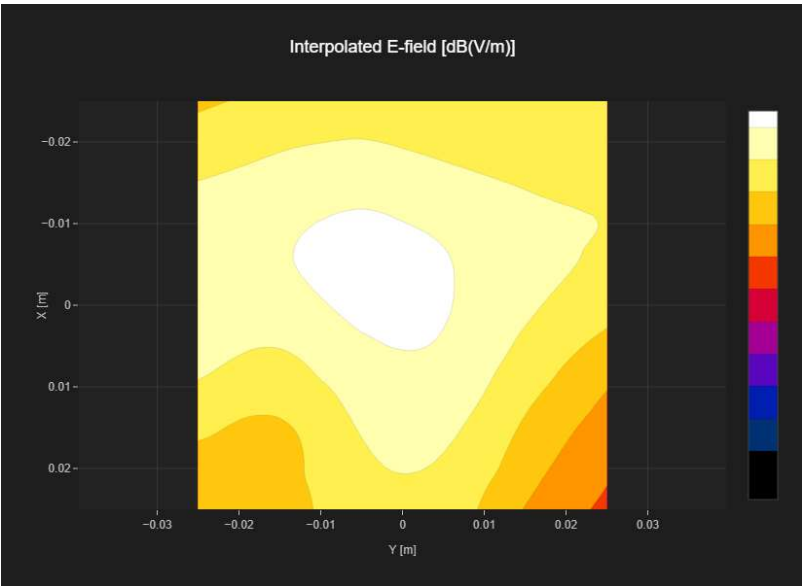
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	633334	3500.01

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
30.3	27.84	-1.64	26.2



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EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

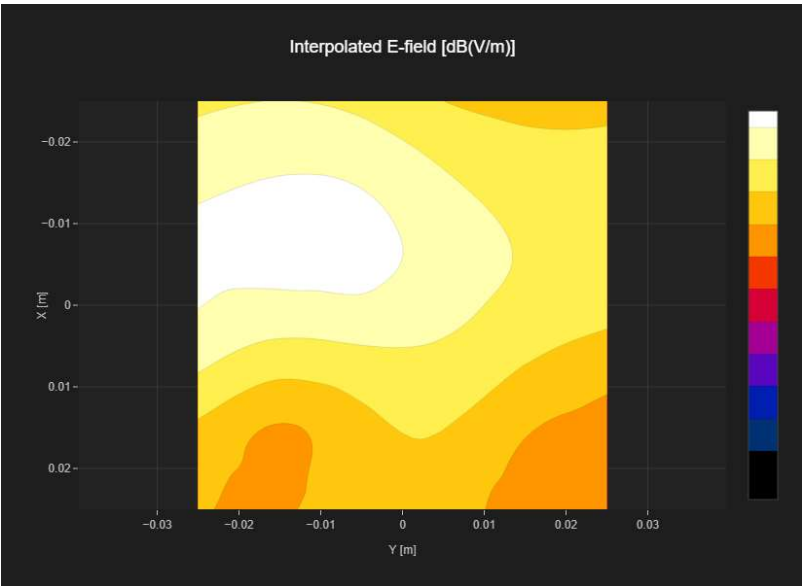
Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	650000	3750.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

E _{max} [dB(V/m)]	E _{avg50x50 max} [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
31.21	28.26	-1.64	26.62



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Hardware Setup

Probe Name	Probe Calibration Date	DAE Name	DAE Calibration Date
EF3DV3 - SN4064	November 13, 2024	DAE4 Sn1670	May 15, 2024

Communication Systems

Band Name	Communication Systems Name	Channel	Frequency [MHz]
Band n77	5G NR (DFT-s-OFDM, 1 RB, 100 MHz, QPSK, 30 kHz)	662000	3930.0

Grid Settings

Extent X [mm]	Extent Y [mm]	Step X [mm]	Step Y [mm]	Distance [mm]
50.0	50.0	10.0	10.0	15.0

Results

Emax [dB(V/m)]	Eavg50x50 max [dB(V/m)]	MIF [dB]	RFail [dB(V/m)]
31.57	28.33	-1.64	26.69

